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RETRACTION





Retraction: Line Trace Effective Comparison Algorithm Based on Wavelet Domain DTW

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Intelligent Automation & Soft Computing has retracted the article titled "Line Trace Effective Comparison Algorithm Based on Wavelet Domain DTW" [1], Intell Automat Soft Comput. 2019;25(2):359–366 at the request of the authors.

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The article duplicates significant parts of a paper published in *Journal of Intelligent & Fuzzy Systems* [2]. One of the conditions of submission of a paper for publication is that authors declare explicitly that the paper has not been previously published and is not under consideration for publication elsewhere. Re-use of any data should be appropriately cited. As such this article represents a misuse of the scientific publishing system.

The article is therefore being retracted at the request of the Editor-in-Chief and the editorial board. All authors have agreed to this retraction. As a responsible publisher, we hold the reliability and integrity of our published content in high regard. We deeply regret any inconvenience caused by this situation to our readers and all concerned parties.

References

- 1. Pan N, Liu Y, Pan D, Qian J, Li G. Line trace effective comparison algorithm based on wavelet domain DTW. Intell Automat Soft Comput. 2019;25(2):359–66. doi:10.31209/2019.100000097.
- 2. Pan N, Kan L, Liu Y, Fu W, Hou Z, Li G, et al. Nonlinear tool traces fast tracing algorithm based on single point laser detection. Journal of Intelligent & Fuzzy Systems. 2019;36(2):1109–20. doi:10.3233/JIFS-169885.

